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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO		
10/711,835	10/08/2004	Ta-Jung Su	13129-US-PA	5834		
31561	1590 10/02/2006		EXAMINER			
JIANQ CHY	UN INTELLECTUAL P	NGUYEN, THANH T				
7 FLOOR-1, 1 ROOSEVELT	NO. 100 ROAD, SECTION 2		ART UNIT	PAPER NUMBER		
TAIPEI, 100	•		2813			
TAIWAN			DATE MAILED: 10/02/2006	DATE MAILED: 10/02/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

		Applica	tion No.	Applicant(s)				
Office Action Summary		10/711,	835	SU ET AL.	SU ET AL.			
		Examin	er	Art Unit				
		Thanh T	T. Nguyen	2813				
Period fo	The MAILING DATE of this commun or Reply	ication appears on t	he cover sheet w	vith the correspondence a	iddress			
WHIC - Exte after - If NC - Failu Any	ORTENED STATUTORY PERIOD F CHEVER IS LONGER, FROM THE M nsions of time may be available under the provisions SIX (6) MONTHS from the mailing date of this comm period for reply is specified above, the maximum state are to reply within the set or extended period for reply reply received by the Office later than three months are ed patent term adjustment. See 37 CFR 1.704(b).	IAILING DATE OF of 37 CFR 1.136(a). In no nunication. atutory period will apply and will, by statute, cause the a	THIS COMMUNI event, however, may a will expire SIX (6) MO application to become A	ICATION. reply be timely filed  NTHS from the mailing date of this BANDONED (35 U.S.C. § 133).				
Status								
1)	Responsive to communication(s) file	ed on 08 October 20	004.					
		2b)⊠ This action is						
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is							
,	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.							
Disposit	ion of Claims							
4) 🖂	Claim(s) <u>1-18</u> is/are pending in the a	application.						
	4a) Of the above claim(s) <u>none</u> is/are withdrawn from consideration.							
	Claim(s) is/are allowed.							
<u> </u>	Claim(s) 1-18 is/are rejected.							
	Claim(s) is/are objected to.							
	Claim(s) are subject to restrict	ction and/or election	requirement.					
Applicat	ion Papers							
_	The specification is objected to by the	e Fyaminer						
<u> </u>	The drawing(s) filed on is/are:		b) objected to	by the Examiner				
. • / 🗀	Applicant may not request that any obje	•	•	•				
	Replacement drawing sheet(s) including		•					
11)	The oath or declaration is objected to							
Priority (	under 35 U.S.C. § 119	·						
12)	Acknowledgment is made of a claim  All b) Some * c) None of:	for foreign priority u	ınder 35 U.S.C.	§ 119(a)-(d) or (f).				
•	1. Certified copies of the priority	documents have be	een received.					
	2. Certified copies of the priority			Application No				
	3. Copies of the certified copies			•	al Stage			
	application from the Internation	nal Bureau (PCT R	ule 17.2(a)).					
* (	See the attached detailed Office actio	on for a list of the ce	rtified copies no	t received.				
Attachmer	et(s)		,					
	æ of References Cited (PTO-892)		<del></del>	Summary (PTO-413)				
3) 🔲 Infor	e of Draftsperson's Patent Drawing Review (Fination Disclosure Statement(s) (PTO-1449 or No(s)/Mail Date			(s)/Mail Date Informal Patent Application (P	TO-152)			
0.0-1			,					

### **DETAILED ACTION**

### Oath/Declaration

Oath/Declaration filed on 10/8/04 has been considered.

## Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

Claims 1-2, 5-6, 13-14, 17-18 are rejected under 35 U.S.C. 102(b) as being anticipated by Takahata et al. (JP Patent No. 05-257167).

Referring to figures 1-4, Takahata et al. teach method of fabricating a gate, comprising the steps of:

providing a substrate (see figure 1a, claim 1, glass substrate);

forming a patterned mask layer over the substrate (see figure 1a and abstract, photoresist mask), wherein the patterned mask layer exposes an area on the substrate for forming the gate (see figure 1a);

forming a gate (Al, see figure 1b) on the substrate within the exposed area; and removing the mask layer (see figure 1c).

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regarding to claims 2, 8, 14, wherein the step of forming the gate further comprises a step of forming a metallic layer (Al is a metal material) over the mask layer and inside the exposed area such that the metallic layer formed over the mask layer is apart from the metallic layer formed inside the exposed area (see figure 1b).

regarding to claims 5, 11, 17, wherein the step of forming the gate comprises performing a physical vapor deposition process (sputtering technique is PVD, see abstract).

Regarding to claim 6, 12, 18, wherein the mask layer comprises a photoresist layer (see figure 1a, and abstract).

Regarding to claim 13. A method of fabricating a pixel unit, comprising the steps of: providing a substrate(see figure 1a, claim 1, glass substrate;

forming a patterned mask layer over the substrate (see figure 1a and abstract, photoresist mask), wherein the patterned mask layer exposes an area on the substrate for forming the gate(see figure 1a);

forming a gate (Al, see figure 1b) on the substrate within the exposed area; removing the mask layer (see figure 1c)

forming an insulating layer (SiN, see figure 2a) over the substrate to cover the gate; forming a channel layer (a-Si, see figure 2b) over the insulating layer above the gate; forming a source and a drain (Cr, see figure 3b) over the channel layer.

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## Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 3-4, 7-12, 15-16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Takahata et al. (JP Patent No. 05-257167) as applied to claims 1-2, 5-6, 13-14, 17-18 above in view of Lee et al. (U.S. Patent Publication No. 2006/0163582).

Takahata et al. teaches a method of forming a thin film transistor as described in the claimed invention above. However, the reference does not teach the step of forming the oxidation-resistant layer is selected from a group consisting of an alloy of metals and a metal silicide compound after forming the metallic layer, and forming a passivation layer over the substrate, wherein the passivation layer has an opening that exposes a portion of the drain; and forming a pixel electrode over the passivation layer such that the pixel electrode is electrically connected to the drain via the opening. Nevertheless, the process is known in fabricating a thin film transistor as evidenced by Lee et al..

Lee et al. teaches the step of forming the oxidation-resistant layer is selected from a group consisting of an alloy of metals and a metal silicide compound after forming the metallic layer (see paragraphs# 47-48, 70, see figures 5a-5b), and forming a passivation layer (70) over the substrate, wherein the passivation layer (70) has an opening (76) that exposes a portion of the drain (66, see figure 5a); and forming a pixel electrode (82, see figure 5a) over the passivation

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layer (70) such that the pixel electrode (82) is electrically connected to the drain (66) via the opening (70, see figure 5b).

Therefore, it would have been obvious to a person of ordinary skill in the requisite art at the time of the invention was made would the step of forming the oxidation-resistant layer is selected from a group consisting of an alloy of metals and a metal silicide compound after forming the metallic layer, and forming a passivation layer over the substrate, wherein the passivation layer has an opening that exposes a portion of the drain; and forming a pixel electrode over the passivation layer such that the pixel electrode is electrically connected to the drain via the opening in process of Takahata et al. in process of Lee et al. because the process is known the semiconductor art to fabricating a thin film transistor to provide superior adhesion ability to the substrate and diffusion resistance.

### **Conclusion**

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Thanh Nguyen whose telephone number is (571) 272-1695, or by Email via address Thanh.Nguyen@uspto.gov. The examiner can normally be reached on Monday-Thursday from 6:00AM to 3:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl Whitehead, Jr., can be reached on (571) 272-1702. The fax phone number for this Group is (571) 273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications Application/Control Number: 10/711,835

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may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pairdirect.uspto.gov. Should you have questions on access to thy Private PAIR system, contact the Electronic Business center (EBC) at 866-217-9197 (toll-free).

Thanh Nguyen Patent Examiner

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